

**Amendments to the Claims**

This listing of claims will replace all prior versions, and listings, of claims in the application:

**Listing of Claims:**

1. (Currently amended) An algorithmic analog-to-digital converter (ADC) comprising:

a sample-and-hold circuit; and

one ADC processing unit, wherein the sample-and-hold circuit and the ADC processing unit operate ~~in parallel~~ in time and share a single operational amplifier.

2. (Original) An algorithmic ADC as claimed in claim 1, wherein the ADC processing unit comprises a multiplying digital-to-analog converter (MDAC) and a sub-ADC.

3. (Original) An algorithmic ADC as claimed in claim 2, wherein the sample-and-hold circuit is integrated with the MDAC.

4. (Original) An algorithmic ADC as claimed in claim 3, wherein the MDAC comprises capacitors that are switchable between a sampled or residue voltage, and reference voltages.

5. (Original) An algorithmic ADC as claimed in claim 4, wherein the sub-ADC generates switch control signals that determine the reference voltages to be applied to the MDAC capacitors.

6. (Original) An algorithmic ADC as claimed in claim 5, and further comprising a clock generator, the clock generator generating a sample-and-hold clock and an ADC clock that is N times faster than the sample-and-hold clock to define N ADC clock cycles per sample-and-hold clock period.

7. (Original) An algorithmic ADC as claimed in claim 6, wherein a triplet of data bits is generated by the ADC processing unit during at least one ADC clock cycle, adding the N triplets of data bits to generate the digital output stream of the algorithmic ADC.

8. (Original) An algorithmic ADC as claimed in claim 7, wherein N=5 to define five ADC cycles per sample-and-hold clock period, five triplets of data bits being added per sample-and-hold clock period to generate an 11-bit digital output per analog input sample.

9. (Currently amended) An algorithmic ADC as claimed in claim 6, wherein each ADC clock cycle is further sub-divided into two phases, wherein during one phase the capacitors are ~~switchehd~~ coupled to a residue or sampled voltage provided by the MDAC, and during another phase the ~~capaeitor~~ capacitors are coupled to a reference voltage determined by the switch control signals generated by the sub-ADC.

10. (Original) A video encoder chip comprising an algorithmic ADC as claimed in claim 1.

11. (Original) A video decoder chip comprising an algorithmic ADC as claimed in claim 1.

12. (Original) A set top box comprising an algorithmic ADC as claimed in claim 1.

13. (Original) An electronic appliance comprising an algorithmic ADC as claimed in claim 1.

14. (Original) A method for converting an input analog signal to an output digital bit stream, comprising:

sampling and holding the input analog signal during a sample-and-hold clock period;

generating N sets of bits during the sample-and-hold clock period using an ADC unit comprising one MDAC and one sub-ADC, wherein the N sets of bits are generated by alternately applying a residue or sampled voltage and a reference voltage to switched capacitors in the MDAC; and

generating the output digital bit stream by adding the N sets of bits.

15. (Original) A method as claimed in claim 14, wherein a single operational amplifier is used to sample and hold the input analog signal and to apply a residue or sampled voltage to the switched capacitors.

16. (Original) A method as claimed in claim 14, wherein five (N=5) sets of bits are generated per sample-and-hold-clock period to yield an 11-bit output digital bit stream when the five sets of bits are added.

17. (Currently amended) A method for converting an input analog signal to an output digital bit stream, comprising:

a step for sampling and holding the input analog signal during a sample-and-hold clock period;

a step for generating an ADC clock having N cycles per sample-and-hold clock period;

a step for generating ~~an intermediate analog~~ a new residue voltage per cycle using the sampled analog signal and previous residue voltages derived from the sampled analog signal;

a step for generating a set of data bits per cycle from the ~~intermediate analog~~ new residue voltage;

a step for generating feedback signals for generating the ~~intermediate analog~~ new residue voltage in the next cycle; and

a step for generating the output digital bit stream using the N sets of data bits.

18. (Currently amended) A method as claimed in claim 17, wherein each cycle is further divided into two phases, and wherein during a first phase a sampled analog signal or residue voltage is applied to the switched capacitors, and wherein during a second phase reference voltages are applied to the switched capacitors.

19. (Original) A method as claimed in claim 18, wherein the feedback signals determine what reference voltages are applied to the switched capacitors.

20. (Original) A method as claimed in claim 19, wherein N=5 and five triplets of data  $d_{\{0,1,2\}^I}$ ,  $d_{\{0,1,2\}^II}$ ,  $d_{\{0,1,2\}^III}$ ,  $d_{\{0,1,2\}^IV}$  and  $d_{\{0,1,2\}^V}$  are generated per sample-and-hold clock period.

21. (Original) A method as claimed in claim 20, wherein an output digital bit stream  $b[10:0]$  is generated by applying the digital reconstruction algorithm

$$\begin{array}{c} d_2^I \ d_1^I \ d_0^I \quad d_2^{III} \ d_1^{III} \ d_0^{III} \quad d_2^V \ d_1^V \ d_0^V \\ d_2^{II} \ d_1^{II} \ d_0^{II} \quad d_2^{IV} \ d_1^{IV} \ d_0^{IV} \quad + \\ \hline b_{10} \ b_9 \ b_8 \ b_7 \ b_6 \ b_5 \ b_4 \ b_3 \ b_2 \ b_1 \ b_0 \end{array}$$

to the five triplets of data.

22. (Original) A method as claimed in claim 18, and further comprising a step for correction of errors using the redundant signed digit (RSD) algorithm.

23. (Currently amended) A system for conversion of an analog input signal to an output digital bit stream comprising:

means for sampling and holding an input analog signal;

means for applying the sampled and held signal to a switched capacitor circuit;

means for generating a residue voltage with the switched capacitor circuit;

means for generating N sets of data bits from the residue voltage per sampled and held signal; and

means for generating feedback signals corresponding to the data bits to control reference voltages applied to the switched capacitor circuit, wherein the means for sampling and holding an input signal, means for applying the sampled and held signal to a switched capacitor circuit, and means for generating a residue voltage comprise a single operational amplifier.

24. (Canceled)

25. (Original) A system as claimed in claim 23, wherein the means for generating N sets of data bits comprises a sub-ADC having a flash architecture.

26. (Original) A system as claimed in claim 25, wherein the switched capacitor circuit is contained within an MDAC, and a sample-and-hold circuit is integrated in the MDAC.

27. (Original) A system as claimed in claim 26, and further comprising clock generation means for generating a first clock governing operation of the sample-and-hold circuit and a second clock governing operation of the MDAC and sub-ADC.

28. (Original) A system as claimed in claim 27, wherein the second clock is N times faster than the first clock.